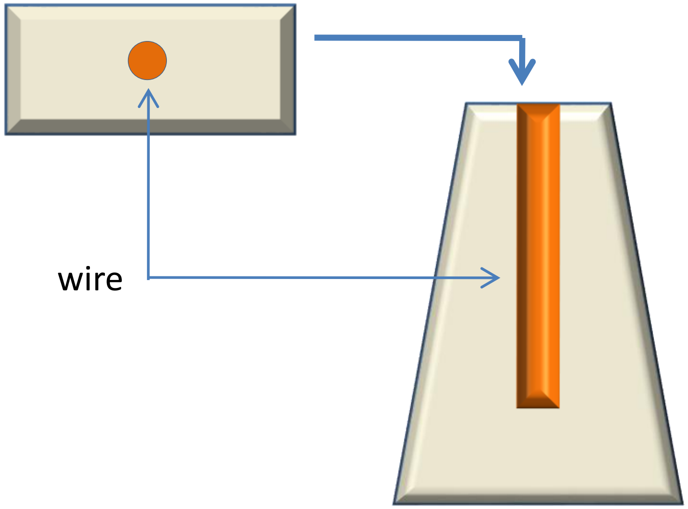
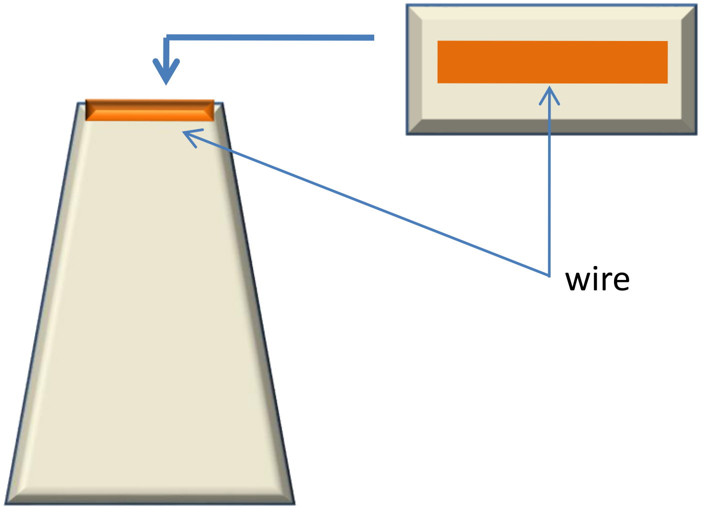
ROG MICROSCOPY & CONSULTING SERVICES LLC
3702 N.Highway A1A (Suite 802), Fort Pierce, FL 34949-8552
Email: rogmicro@gmail.com Telephone: 585-503-4050

Case Study: Preparation of Pt/Pd wire (0.008” Diameter) sample for Scanning Electron Microscopy (SEM) or Infrared Analysis (IR).

The wire was prepared for Cross section by embedding in epoxy and facing off using a Leica 2165 Microtome equipped with a diamond knife. The faceoff plug can be examined using Reflected Optical Microscopy or mounted onto a 45° SEM stub, or dry cross sections placed on flat SEM stubs for examination in a Scanning Electron Microscope.

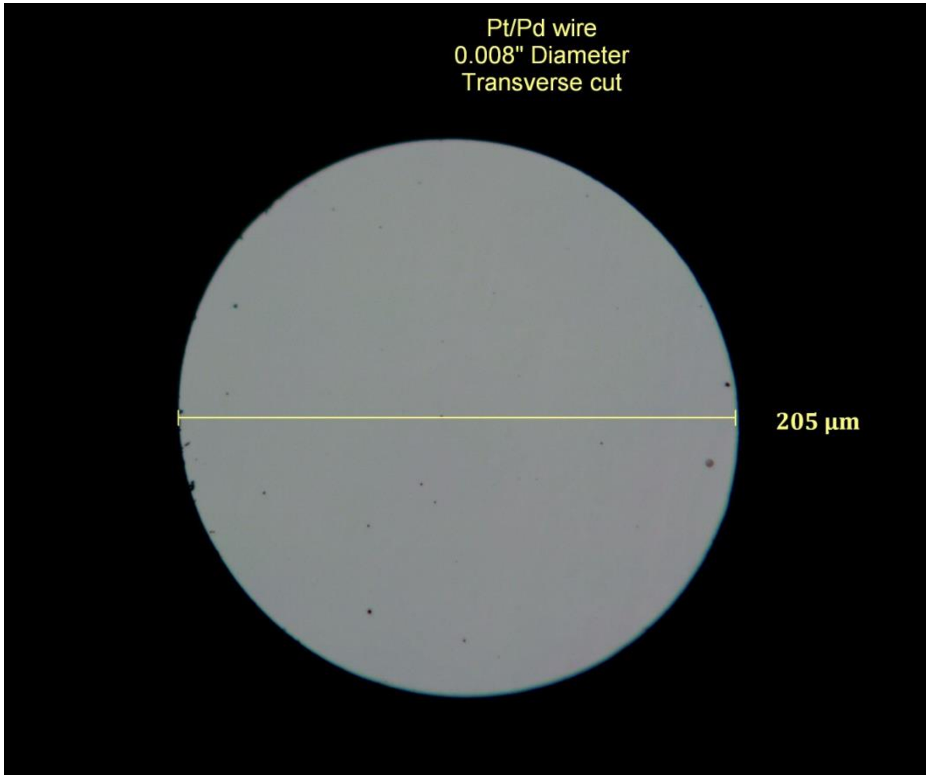


Transverse cut

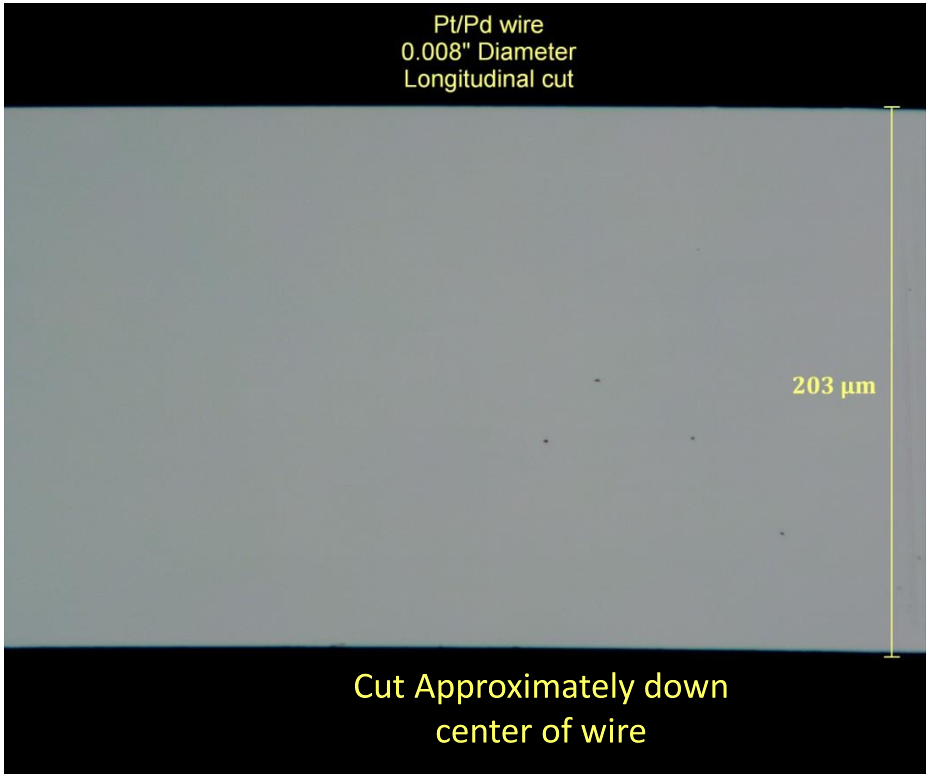


Longitudinal cut

Faced off plug imaged using an Olympus BX60 Microscope. Sections can also be placed on salt crystals or microscope slides dry for IR analysis.



Transverse cut
Reflected BF



Longitudinal cut
Reflected BF